

**Four-two-three-two-input AND-OR-invert gate****54F64****ORDERING INFORMATION**

DESCRIPTION	ORDER CODE	PACKAGE DESIGNATOR*
14-Pin Ceramic DIP	54F64/BCA	GDIP1-T14
14-Pin Ceramic Flat Pack	54F64/BDA	GDFP1-F14
20-Pin Ceramic LLCC	54F64/B2A	CQCC2-N20

\* MIL-STD 1835 or Appendix A of 1995 Military Data Handbook

**FUNCTION TABLE**

INPUTS												OUTPUT
A	B	C	D	E	F	G	H	J	K	L	Y	
H	H	X	X	X	X	X	X	X	X	X	L	
X	X	H	H	H	H	X	X	X	X	X	L	
X	X	X	X	X	X	H	H	H	X	X	L	
X	X	X	X	X	X	X	X	X	H	H	L	
All other combinations												H

H = High voltage level

L = Low voltage level

X = Don't care

**INPUT AND OUTPUT LOADING AND FAN-OUT TABLE**

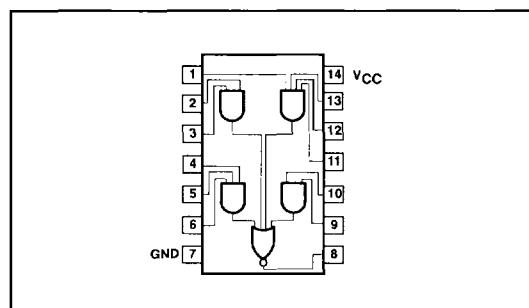
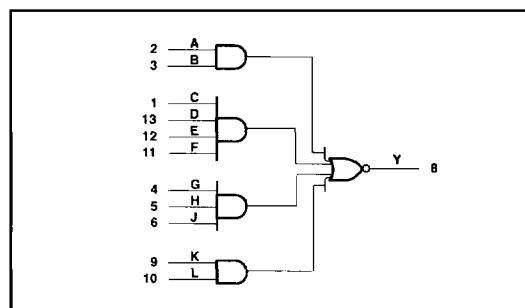
PINS	DESCRIPTION	54F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
A - L	Inputs	1.0/1.0	20µA/0.6mA
Q <sub>0</sub> - Q <sub>7</sub>	Outputs	50/33	1.0mA/20mA

NOTE: One (1.0) FAST Unit Load (U.L.) is defined as: 20µA in the High state and 0.6mA in the Low state.

**ABSOLUTE MAXIMUM RATINGS**

(Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

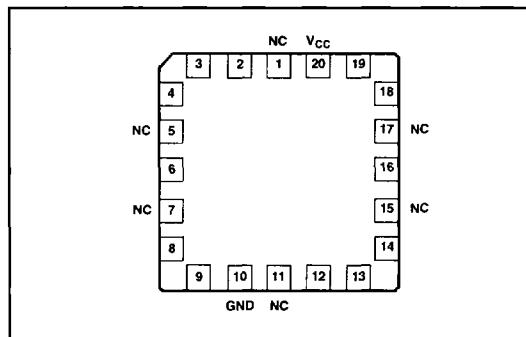
SYMBOL	PARAMETER	RATING	UNIT
V <sub>CC</sub>	Supply voltage range	-0.5 to +7.0	V
V <sub>I</sub>	Input voltage range	-0.5 to +7.0	V
I <sub>I</sub>	Input current range	-30 to +5.0	mA
V <sub>O</sub>	Voltage applied to output in High output state range	-0.5 to +V <sub>CC</sub>	V
I <sub>O</sub>	Current applied to output in Low output state	40	mA
T <sub>STG</sub>	Storage temperature range	-65 to +150	°C

**PIN CONFIGURATION****LOGIC SYMBOL**

## Four-two-three-two-input AND-OR-invert gate

54F64

## LLCC LEAD CONFIGURATION



## RECOMMENDED OPERATING CONDITIONS

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
$V_{CC}$	Supply voltage	4.5	5.0	5.5	V
$V_{IH}$	High-level input voltage	2.0			V
$V_{IL}$	Low-level input voltage			0.8	V
$I_{IK}$	Input clamp current			-18	mA
$I_{OH}$	High-level output current			-1	mA
$I_{OL}$	Low-level output current			20	mA
$T_A$	Operating free-air temperature range	-55		+125	$^{\circ}\text{C}$

## DC ELECTRICAL CHARACTERISTICS

(Over recommended operating free-air temperature unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS <sup>1</sup>	LIMITS			UNIT
			Min	Typ <sup>2</sup>	Max	
$V_{OH}$	High-level output voltage	$V_{CC} = \text{Min}$ , $V_{IL} = \text{Max}$ , $I_{OH} = \text{Max}$ , $V_{IH} = \text{Min}$	2.5			V
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{Min}$ , $V_{IL} = \text{Max}$ , $I_{OL} = \text{Max}$ , $V_{IH} = \text{Min}$		0.35	0.50	V
$V_{IK}$	Input clamp voltage	$V_{CC} = \text{Min}$ , $I_I = I_{IK}$		-0.73	-1.2	V
$I_{IH2}$	Input current at maximum input voltage	$V_{CC} = \text{Max}$ , $V_I = 7.0\text{V}$			100	$\mu\text{A}$
$I_{iH1}$	High-level input current	$V_{CC} = \text{Max}$ , $V_I = 2.7\text{V}$		1	20	$\mu\text{A}$
$I_{iL}$	Low-level input current	$V_{CC} = \text{Max}$ , $V_I = 0.5\text{V}$		-0.4	-0.6	mA
$I_{os}$	Short-circuit output current <sup>3</sup>	$V_{CC} = \text{Max}$ , $V_O = 0.0\text{V}$	-60	-80	-150	mA
$I_{CC}$	Supply current (total)	$V_{CC} = \text{Max}$	$V_I = \text{GND}$	1.9	2.8	mA
	$I_{CCH}$		$V_I \geq 4.0\text{V}$	3.1	4.7	mA

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54F64

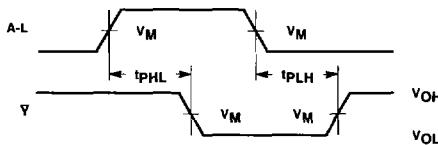
## AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITIONS	LIMITS					UNIT	
			$T_A = +25^\circ\text{C}, V_{CC} = +5.0\text{V}$		$T_A = -55^\circ\text{C} \text{ to } +125^\circ\text{C}$				
			$C_L = 50\text{pF}$	$R_L = 500\Omega$	$V_{CC} = +5.0\text{V} \pm 10\%$	$C_L = 50\text{pF}, R_L = 500\Omega$			
$t_{PLH}$	Propagation delay A-L to $\bar{Y}$	Waveform NO TAG	1.5	4.6	6.0	1.0	8.0	ns	
$t_{PHL}$			1.5	3.2	4.5	1.0	6.5	ns	

## NOTES:

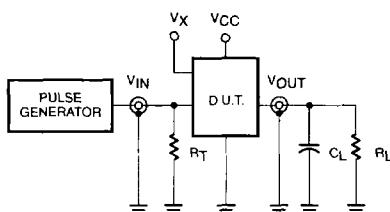
- For conditions shown as Min or Max, use the appropriate value specified under recommended operating conditions for the applicable type and function table for operating mode.
- All typical values are at  $V_{CC} = 5\text{V}$ ,  $T_A = 25^\circ\text{C}$ .
- Not more than one output should be shorted at a time. For testing  $I_{OS}$ , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests,  $I_{OS}$  tests should be performed last.

## AC WAVEFORM

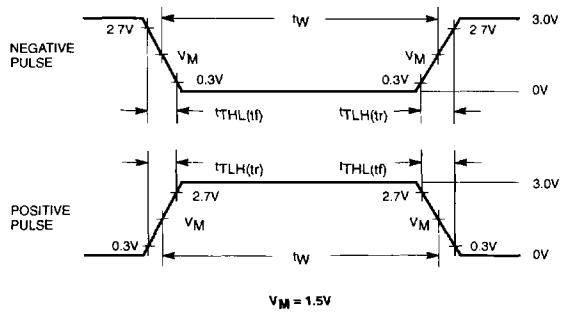
NOTE: For all waveforms,  $VM = 1.5\text{V}$ .

Waveform 1. For Inverting Outputs

## TEST CIRCUIT AND WAVEFORM



Test Circuit for Totem-Pole Outputs



Input Pulse Definition

## DEFINITIONS:

- $R_L$  = Load Resistor; see AC Characteristics for value.  
 $C_L$  = Load capacitance includes jig and probe capacitance; see AC Characteristics for value.  
 $R_T$  = Termination resistance should be equal to  $Z_{OUT}$  of pulse generators.  
 $t_{TLH}, t_{THL}$  = Values should be less than or equal to the table entries.  
 $V_X$  = Unclocked pins must be held at:  $\leq 0.8\text{V}$ ;  $\geq 2.7\text{V}$  or open per FunctionTable.

INPUT PULSE CHARACTERISTICS				
Family	Rep. Rate	Pulse Width	$t_{TLH}$	$t_{THL}$
54F	1MHz	500ns	$\leq 2.5\text{ns}$	$\leq 2.5\text{ns}$